Notice of References Cited Application/Control No. 10/598,025 Examiner KENNETH CHANG Applicant(s)/Patent Under Reexamination DE HAAN ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-5,801,781 A	09-1998	Hiroshima et al.	348/441
*	В	US-2003/0174837 A1	09-2003	Candelore et al.	380/210
*	O	US-2004/0109671 A1	06-2004	Kuno et al.	386/068
*	D	US-2005/0105896 A1	05-2005	Kochale, Axel	386/111
	Е	US-			
	F	US-			
	G	US-			
	Ι	US-			
	_	US-			
	7	US-			
	K	US-			
	┙	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	х	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.